

L Number	Hits	Search Text	DB	Time stamp
1	4416	ion adj beam adj etch\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/27 10:53
2	472	(ion adj beam adj etch\$3) and focus\$3 near ion adj beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/27 12:10
3	128	((ion adj beam adj etch\$3) and focus\$3 near ion adj beam) and (etch\$3 remov\$3 strip\$4) near (resist photoresist organic metal\$3 conduct\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/27 10:55
4	92	((ion adj beam adj etch\$3) and focus\$3 near ion adj beam) and (etch\$3 remov\$3 strip\$4) adj (resist photoresist organic metal\$3 conduct\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/27 10:56
5	22	((((ion adj beam adj etch\$3) and focus\$3 near ion adj beam) and (etch\$3 remov\$3 strip\$4) adj (resist photoresist organic metal\$3 conduct\$3)) and (etch\$3 remov\$3 strip\$4) adj (resist photoresist organic metal\$3 conduct\$3) with beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/27 10:56
6	1687	(ion adj beam adj etch\$3) and focus\$3 near ion adj beam FIB and etch\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/27 12:12
7	1243	((focus\$3 near ion near beam) FIB) with etch\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/27 12:13
8	3	((focus\$3 near ion near beam) FIB) with etch\$3 same organic adj (film layer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/27 12:18
9	0	20010027029.URPN.	USPAT	2004/02/27 12:17
10	3	((focus\$3 near ion near beam) FIB) same etch\$3 same organic adj (film layer)not (((focus\$3 near ion near beam) FIB) with etch\$3 same organic adj (film layer))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/27 12:20
11	26	((focus\$3 near ion near beam) FIB) same etch\$3 and organic adj (film layer) not (((focus\$3 near ion near beam) FIB) with etch\$3 same organic adj (film layer)) (((focus\$3 near ion near beam) FIB) same etch\$3 same organic adj (film layer)not (((focus\$3 near ion near beam) FIB) with etch\$3 same organic adj (film layer))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/27 12:42
12	20	((focus\$3 near ion near beam) FIB) and conduct\$4 near organic	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/27 12:42